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(54) Title: VOLTAGE SOURCE MEASUREMENT UNIT WITH MINIMIZED COMMON MODE ERRORS

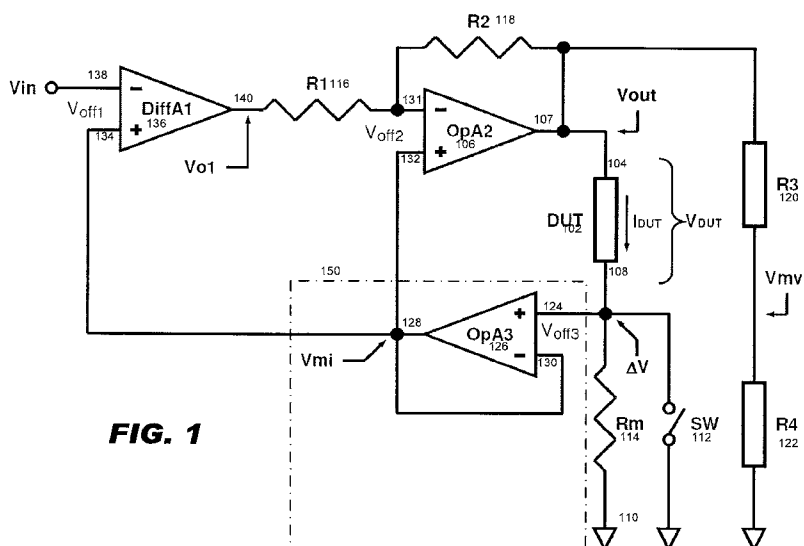


FIG. 1

(57) Abstract: A particular configuration of voltage source measurement (VSM) circuitry minimizes common mode errors in measurement of current through a device under test (DUT), even across a wide range of output voltages. The current I_{DUT} is not affected by common-mode errors, since the current measurement is based on the output voltage of an operational amplifier or a differential amplifier, and the circuit configuration is such that the current measurement is made while the operation amplifier or differential amplifier has very low common-mode input voltage.